Electronic Supplemental Information (ESI)

Cross-sectional analysis of the core of silicon microparticles formed via zinc reduction of $SiCl_4$

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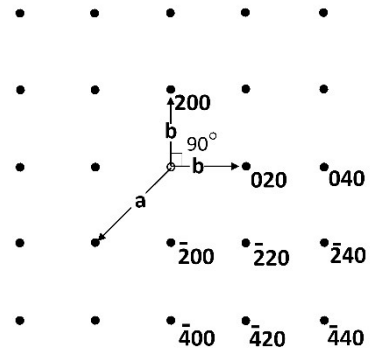

Fig. S1 Electron diffraction pattern for diamond structures. The incident direction of electron beam is [001]. Length ratio of vector a/b = 1.414. Original data from ref. 29 in the main manuscript.

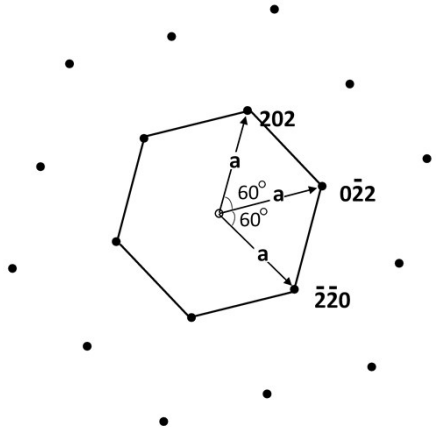

Fig. S2 Electron diffraction pattern for diamond structures. The incident direction of electron beam is [$\bar{1}11$]. Original data from ref. 29 in the main manuscript. Regular hexagon is drawn using six spots from {220} planes as shown in this figure.

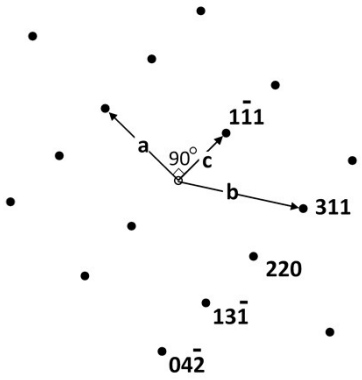

Fig. S3 Electron diffraction pattern for diamond structures. The incident direction of electron beam is

[$\bar{1}12$]. Length ratios of vectors are b/c = 1.633 and a/c = 1.915, respectively. Original data from ref. 29 in the main manuscript.